

Gallium Nitride: Dry Etching and Wet Etching

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- Etching for further formation of ohmic contacts
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- Etch rate
- Selectivity with PHR and dielectrics
- Isotropy control
- Repeatability
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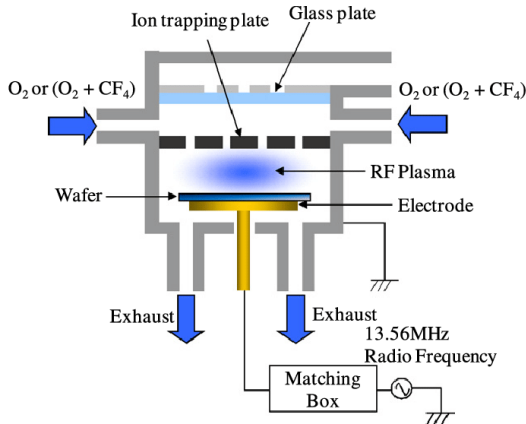
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	Dry Etching	Wet etching
Etch rate	Lower	Higher
Isotropy control	Very good	Poor
Repeatability	Excellent	Good
Cost	Higher (gases + electricity)	Lower
Equipment required	Complex (Vaccum, MFCs)	Very simple
Sample damage	Higher	Lower

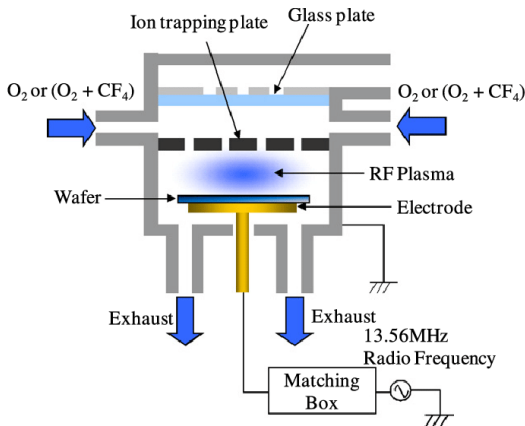
RIE - Reactive ion etching

- Combination of Physical and chemical etching
- Physical = non-reactive ions
- Chemical = reactive ions
- Mostly using *C/* based gases for GaN



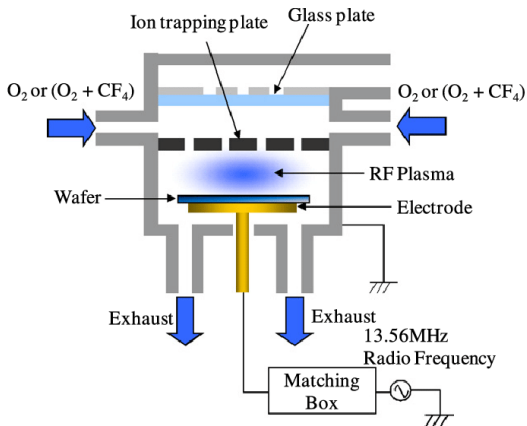
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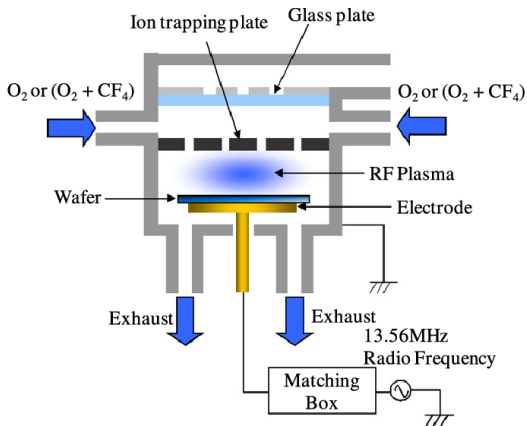
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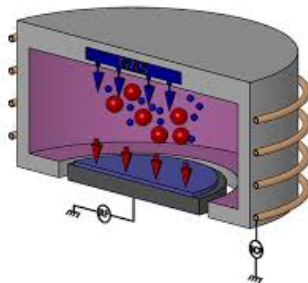
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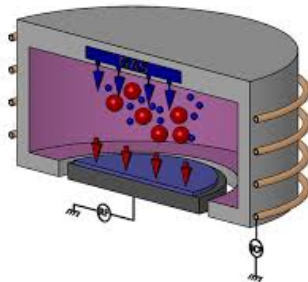
ICP RIE - Inductively Coupled Plasma

- Similar to RIE, but magnetic field generated plasma
- Much denser plasma and consequently higher etch rate
- Tends to be more isotropic
- Possible to combine with common RIE in same process



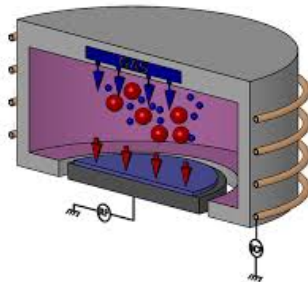
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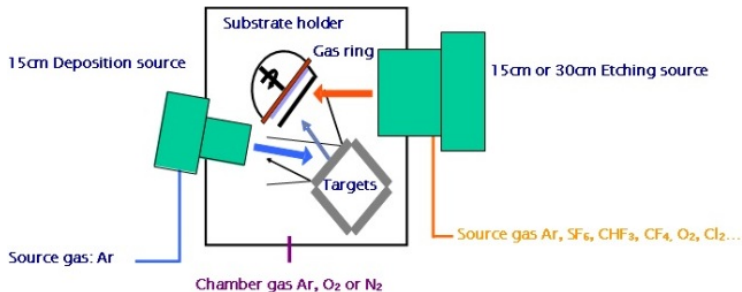
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RIBE - Reactive Ion Beam Etching

Uses an Ion Beam instead of plasma+gases



ECR - Electron Cyclotron Resonance Plasma

- Ultra-Low Pressure and Highest Density Plasma
- Plasma distribution and height control
- Ion and radical control
- Temperature control

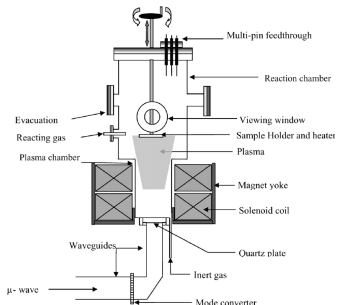


Photo Assisted Dry Etching

- Simultaneous exposure of reactive gas and UV laser radiation
- Laser interaction with the surface, bulk and reactants leads to bondbreaking and desorption of reactant.
- Promising for achieving damage-free etching
- For GaN, HCl with ArF (193nm) laser is typically used

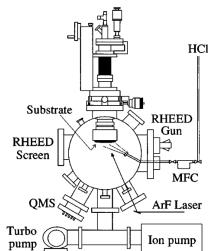


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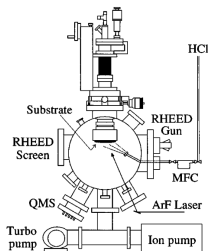
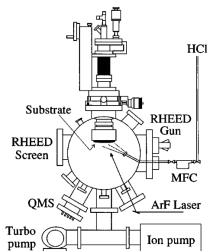


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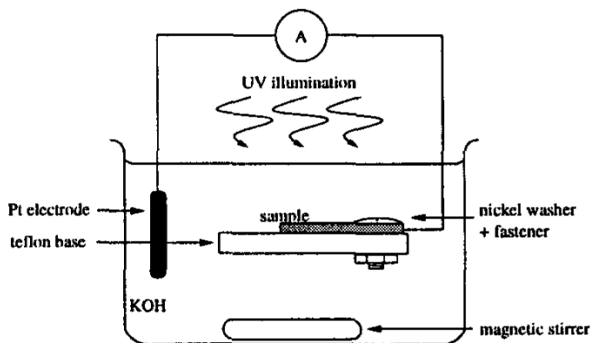
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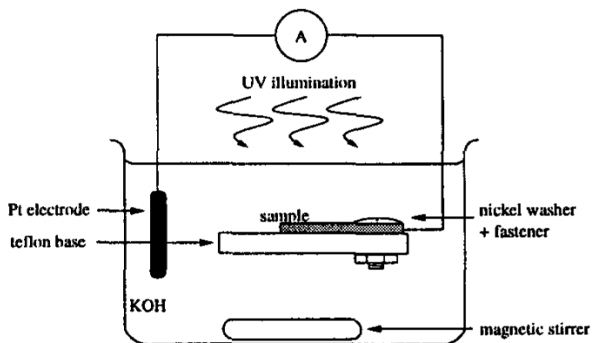
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UV+KOH

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- Definition of important etching parameters will be stated.
- General aspects of dry and wet etching will be explained.
- Specific Dry and Wet Etching for GaN techniques will be reviewed, focusing on the ones available at CNEA CAC DMNT. More wet etch techniques are to be studied.
- Outlook
 - Get consistent data for comparison
 - Presentation of the information and conclusions

For Further Reading I



J. Lee et al.

Dry Etching of GaN and Related Materials: Comparison of Techniques.

IEEE Journal of Selected Topics in Quantum Electronics, 1998.



B. Kinder and T. Tansley.

A Comparative Study of Photoenhanced Wet Chemical Etching and Reactive Ion Etching of GaN Epilayers Grown on Various Substrates

Conference on Optoelectronic and Microelectronic Materials and Devices. Proceedings (Cat. No.98EX140), 1999.